

**Search Notes**

Application/Control No.

10/681,517

Examiner

Hai L. Nguyen

Applicant(s)/Patent under  
Reexamination

LO ET AL.

Art Unit

2816

**SEARCHED**

Class	Subclass	Date	Examiner
331	16-18,10, 11,1A,25, DIG.2	3/31/2005	HLN
327	147,148		
	150,156		
	157,159		
	162,163		
375	373-376		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	4/2/2005	HLN